




PCN Number:	20190516001.1		PCN Date:	May 21, 2019																			
Title:	Transfer of select C10 devices from ANAM-1 to DMOS5 Wafer Fab site																						
Customer Contact:	PCN Manager		Dept:	Quality Services																			
Proposed 1st Ship Date:	Aug 21, 2019	Estimated Sample Availability:		Date provided at sample request.																			
Change Type:																							
<input type="checkbox"/>	Assembly Site	<input type="checkbox"/>	Assembly Process	<input type="checkbox"/>	Assembly Materials																		
<input type="checkbox"/>	Design	<input type="checkbox"/>	Electrical Specification	<input type="checkbox"/>	Mechanical Specification																		
<input type="checkbox"/>	Test Site	<input type="checkbox"/>	Packing/Shipping/Labeling	<input type="checkbox"/>	Test Process																		
<input type="checkbox"/>	Wafer Bump Site	<input type="checkbox"/>	Wafer Bump Material	<input type="checkbox"/>	Wafer Bump Process																		
<input checked="" type="checkbox"/>	Wafer Fab Site	<input type="checkbox"/>	Wafer Fab Materials	<input type="checkbox"/>	Wafer Fab Process																		
		<input type="checkbox"/>	Part number change																				
PCN Details																							
Description of Change:																							
This change notification is to announce the transfer of select devices from ANAM-1 to the DMOS5 Wafer Fab site. Fab support from ANAM-1 has been discontinued. Buffer inventory has been built to cover the notification period of this change notification.																							
<table border="1"> <thead> <tr> <th colspan="3">Current (Discontinued)</th> <th colspan="3">New (Transfer to Location)</th> </tr> <tr> <th>Current Fab Site</th> <th>Fab Process</th> <th>Wafer Diameter</th> <th>New Fab Site</th> <th>Fab Process</th> <th>Wafer Diameter</th> </tr> </thead> <tbody> <tr> <td>ANAM-1</td> <td>C10</td> <td>200mm</td> <td>DMOS5</td> <td>C10</td> <td>200mm</td> </tr> </tbody> </table>						Current (Discontinued)			New (Transfer to Location)			Current Fab Site	Fab Process	Wafer Diameter	New Fab Site	Fab Process	Wafer Diameter	ANAM-1	C10	200mm	DMOS5	C10	200mm
Current (Discontinued)			New (Transfer to Location)																				
Current Fab Site	Fab Process	Wafer Diameter	New Fab Site	Fab Process	Wafer Diameter																		
ANAM-1	C10	200mm	DMOS5	C10	200mm																		
Qual details are provided in the Qual Data Section.																							
Reason for Change:																							
Discontinued Fab support from ANAM-1																							
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):																							
None																							
Changes to product identification resulting from this PCN:																							
Current																							
Chip Site	Chip Site Origin (20L)	Chip Site Country Code (21L)	Chip Site City																				
ANAM-1	ANM	KOR	Bucheon-si																				
New Fab Site																							
Chip Site	Chip Site Origin (20L)	Chip Site Country Code (21L)	Chip Site City																				
DP1DM5	DM5	USA	Dallas																				
Sample product shipping label (not actual product label)																							
   <div style="float: right;"> <p>(1P) SN74LS07NSR (Q) 2000 (D) 0336 (31T) LOT: 3959047MLA (4W) TKY (1T) 7523483S12 (P) (2P) REV: (V) 0033317 (20L) CS0: SHE (21L) CCO: USA (22L) AS0: MLA (23L) ACO: MYS</p> </div> <p>MADE IN: Malaysia 2DC: 20: MSL 2 /260C/1 YEAR SEAL DT MSL 1 /235C/UNLIM 03/29/04 OPT: ITEM: 39 LBL: 5A (L)T0:1750</p>																							
Product Affected Group:																							
CDCVF2310PW	CDCVF2505DG4	CDCVF2505PWRG4	HPA00771PWR																				
CDCVF2310PWG4	CDCVF2505DR	CDCVF25081PW	SN65LV1023ADB																				

CDCVF2310PWR	CDCVF2505DRG4	CDCVF25081PWG4	SN65LV1023ADBR
CDCVF2310PWRG4	CDCVF2505PW	CDCVF25081PWR	SN65LV1023ARHBR
CDCVF2505D	CDCVF2505PWR	CDCVF25081PWRG4	SN65LV1023ARHBT

Qualification Report

Approve Date 7-May-2019

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: CDCVF2310PW	QBS Reference: TLK2500IRCP	QBS Reference: TLK2201BIRCP
AC	Autoclave 121C, 2atm	96 Hours	-	3/231/0	3/231/0
CDM	ESD - CDM	1000 V	1/3/0	-	-
ED	Electrical Characterization	Per Data Sheet Parameters	Pass	-	-
HAST	Biased HAST, 130C/85%RH	96 Hours	-	3/231/0	-
HBM	ESD - HBM	4000 V	1/3/0	-	-
HTOL	Life Test, 155C	240 Hours	-	3/231/0	-
HTSL	High Temp. Storage Bake, 170C	420 Hours	-	3/135/0	3/135/0
LU	Latch-up	(Per JESD78)	1/6/0	-	-
T/C	Temp Cycle -65C/150C	500 Cycles	-	-	3/231/0

- Qual Devices qualified at LEVEL1-260CG: CDCVF2310PW

- QBS: Qual By Similarity

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

Qualification Report

Approve Date 7-May-2019

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: SN65LV1023ADB	QBS Reference: TLK2500IRCP	QBS Reference: TLK2201BIRCP
AC	Autoclave 121C, 2atm	96 Hours	-	3/231/0	3/231/0
CDM	ESD - CDM	1000 V	1/3/0	-	-
ED	Electrical Characterization	Per Data Sheet Parameters	Pass	-	-
HAST	Biased HAST, 130C/85%RH	96 Hours	-	3/231/0	-
HBM	ESD - HBM	3000 V	1/3/0	-	-
HTOL	Life Test, 155C	240 Hours	-	3/231/0	-
HTSL	High Temp. Storage Bake, 170C	420 Hours	-	3/135/0	3/135/0
LU	Latch-up	(Per JESD78)	1/6/0	-	-
T/C	Temp Cycle -65C/150C	500 Cycles	-	-	3/231/0

- Qual Devices qualified at LEVEL1-260CG: SN65LV1023ADB

- QBS: Qual By Similarity

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below, or you can contact your local Field Sales Representative.

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